Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/805,890	NALLAN ET AL.	
Examiner	Art Unit	
Binh X. Tran	1765	

SEARCHED					
SEARONED					
Class	Subclass	Date	Examiner		
216	58	12/20/2006	ВТ		
216	68	12/20/2006	ВТ		
216	89	12/20/2006	вт		
438	722	12/20/2006	ВТ		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Update search using USPAT, USPG- PUB, JPO, EPO, DERWENT, IBM_TDB databases	12/20/2006	ВТ		
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